

Search Notes

Application/Control No.

10/588,582

Examiner

Evan Dzierzynski

Applicant(s)/Patent under
Reexamination

GEYER, JOHANNES

Art Unit

2875

SEARCHED

Class	Subclass	Date	Examiner
362	253	1/2/2008	ED
	92,94	1/2/2008	ED
	234	1/2/2008	ED
68	196	1/2/2008	ED

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Consulted with Sharon Payne	1/2/2008	ED
EAST search, attached	1/2/2008	ED